

# DATA SHEET

## **BF1211; BF1211R; BF1211WR** N-channel dual-gate MOS-FETs

Product specification

2003 Dec 16

# N-channel dual-gate MOS-FETs

# BF1211; BF1211R; BF1211WR

## FEATURES

- Short channel transistor with high forward transfer admittance to input capacitance ratio
- Low noise gain controlled amplifier
- Excellent low frequency noise performance
- Partly internal self-biasing circuit to ensure good cross-modulation performance during AGC and good DC stabilization.

## APPLICATIONS

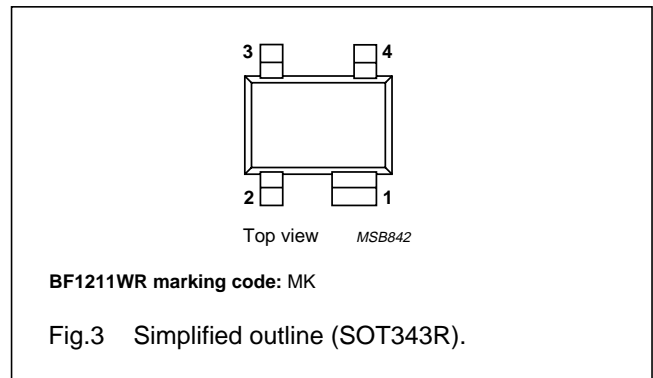
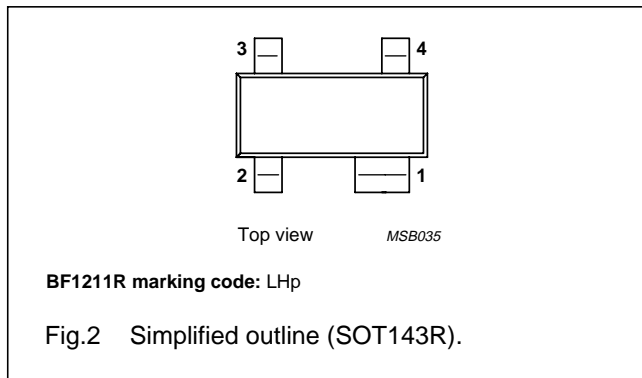
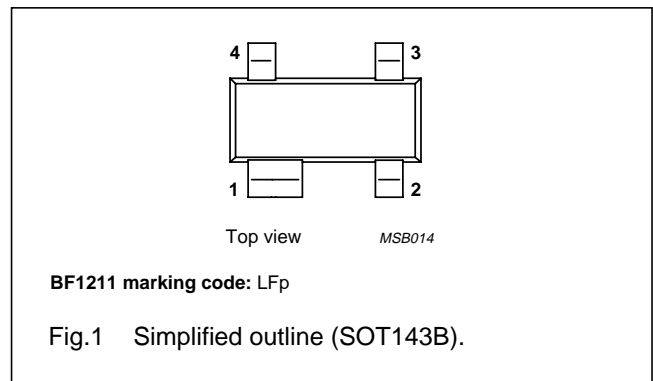
- Gain controlled low noise VHF and UHF amplifiers for 5 V digital and analog television tuner applications.

## DESCRIPTION

Enhancement type N-channel field-effect transistor with source and substrate interconnected. Integrated diodes between gates and source protect against excessive input voltage surges. The BF1211, BF1211R and BF1211WR are encapsulated in the SOT143B, SOT143R and SOT343R plastic packages respectively.

## PINNING

PIN	DESCRIPTION
1	source
2	drain
3	gate 2
4	gate 1



## QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{DS}$	drain-source voltage		–	–	6	V
$I_D$	drain current		–	–	30	mA
$P_{tot}$	total power dissipation		–	–	180	mW
$ y_{fs} $	forward transfer admittance		25	30	40	mS
$C_{ig1-ss}$	input capacitance at gate 1		–	2.1	2.6	pF
$C_{rss}$	reverse transfer capacitance	$f = 1 \text{ MHz}$	–	15	30	fF
F	noise figure	$f = 400 \text{ MHz}$	–	0.9	1.6	dB
$X_{mod}$	cross-modulation	input level for $k = 1\%$ at 40 dB AGC	100	105	–	dB $\mu$ V
$T_j$	junction temperature		–	–	150	°C

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**CAUTION**

This product is supplied in anti-static packing to prevent damage caused by electrostatic discharge during transport and handling. For further information, refer to Philips specs.: SNW-EQ-608, SNW-FQ-302A and SNW-FQ-302B.

**ORDERING INFORMATION**

TYPE NUMBER	PACKAGE		
	NAME	DESCRIPTION	VERSION
BF1211	–	plastic surface mounted package; 4 leads	SOT143B
BF1211R	–	plastic surface mounted package; reverse pinning; 4 leads	SOT143R
BF1211WR	–	plastic surface mounted package; reverse pinning; 4 leads	SOT343R

**LIMITING VALUES**

In accordance with the Absolute Maximum Rating System (IEC 60134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{DS}$	drain-source voltage		–	6	V
$I_D$	drain current (DC)		–	30	mA
$I_{G1}$	gate 1 current		–	$\pm 10$	mA
$I_{G2}$	gate 2 current		–	$\pm 10$	mA
$P_{tot}$	total power dissipation				
	BF1211; BF1211R	$T_s \leq 116\text{ °C}$ ; note 1	–	180	mW
	BF1211WR	$T_s \leq 122\text{ °C}$ ; note 1	–	180	mW
$T_{stg}$	storage temperature		–65	+150	°C
$T_j$	junction temperature		–	150	°C

**Note**

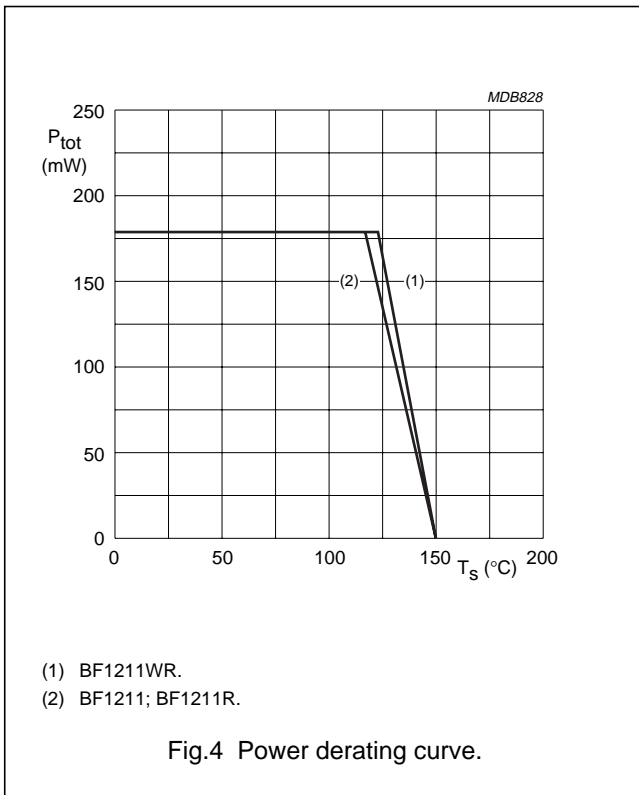
1.  $T_s$  is the temperature of the soldering point of the source lead.

**THERMAL CHARACTERISTICS**

SYMBOL	PARAMETER	VALUE	UNIT
$R_{th(j-s)}$	thermal resistance from junction to soldering point		
	BF1211; BF1211R	185	K/W
	BF1211WR	155	K/W

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**STATIC CHARACTERISTICS**

$T_j = 25\text{ }^\circ\text{C}$  unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{G1-S} = V_{G2-S} = 0\text{ V}; I_D = 10\text{ }\mu\text{A}$	6	–	V
$V_{(BR)G1-SS}$	gate 1-source breakdown voltage	$V_{G2-S} = V_{DS} = 0\text{ V}; I_{G1-S} = 10\text{ mA}$	6	10	V
$V_{(BR)G2-SS}$	gate 2-source breakdown voltage	$V_{G1-S} = V_{DS} = 0\text{ V}; I_{G2-S} = 10\text{ mA}$	6	10	V
$V_{(F)S-G1}$	forward source-gate 1 voltage	$V_{G2-S} = V_{DS} = 0\text{ V}; I_{S-G1} = 10\text{ mA}$	0.5	1.5	V
$V_{(F)S-G2}$	forward source-gate 2 voltage	$V_{G1-S} = V_{DS} = 0\text{ V}; I_{S-G2} = 10\text{ mA}$	0.5	1.5	V
$V_{G1-S(th)}$	gate 1-source threshold voltage	$V_{G2-S} = 4\text{ V}; V_{DS} = 5\text{ V}; I_D = 100\text{ }\mu\text{A}$	0.3	1	V
$V_{G2-S(th)}$	gate 2-source threshold voltage	$V_{G1-S} = 5\text{ V}; V_{DS} = 5\text{ V}; I_D = 100\text{ }\mu\text{A}$	0.35	1	V
$I_{DSX}$	drain-source current	$V_{G2-S} = 4\text{ V}; V_{DS} = 5\text{ V}; R_{G1} = 75\text{ k}\Omega;$ note 1	11	19	mA
$I_{G1-S}$	gate 1 cut-off current	$V_{G2-S} = V_{DS} = 0\text{ V}; V_{G1-S} = 5\text{ V}$	–	50	nA
$I_{G2-S}$	gate 2 cut-off current	$V_{G1-S} = V_{DS} = 0\text{ V}; V_{G2-S} = 4\text{ V}$	–	20	nA

**Note**

- $R_{G1}$  connects  $G_1$  to  $V_{GG} = 5\text{ V}$ .

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**DYNAMIC CHARACTERISTICS**Common source;  $T_{amb} = 25\text{ °C}$ ;  $V_{G2-S} = 4\text{ V}$ ;  $V_{DS} = 5\text{ V}$ ;  $I_D = 15\text{ mA}$ ; unless otherwise specified.

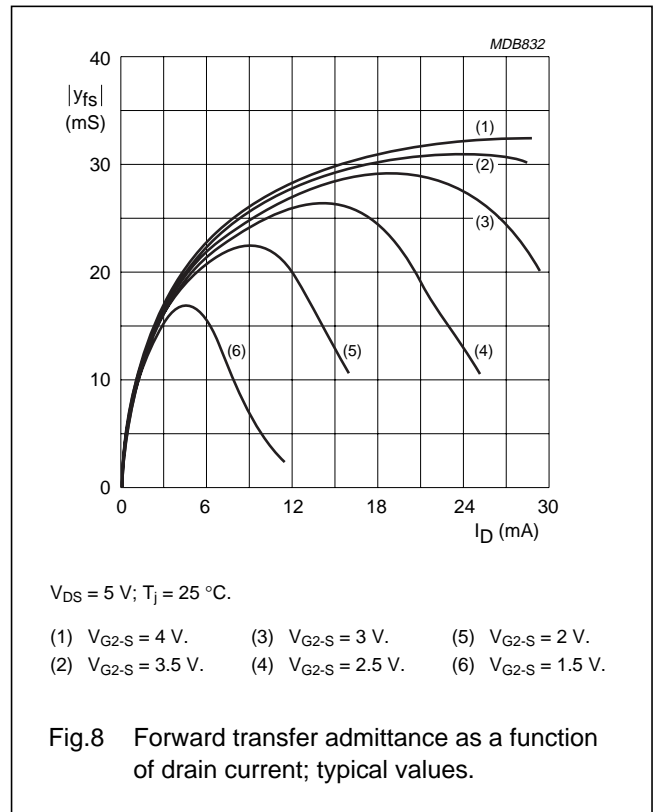
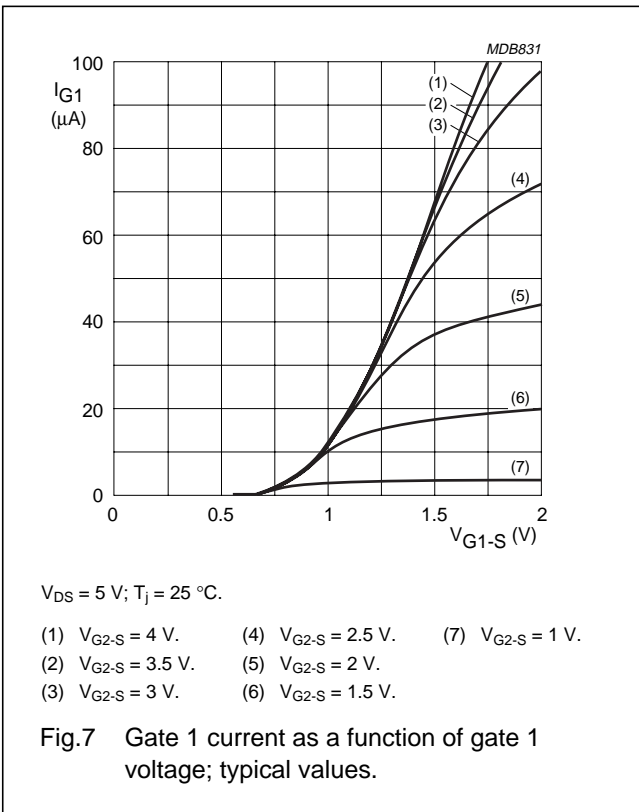
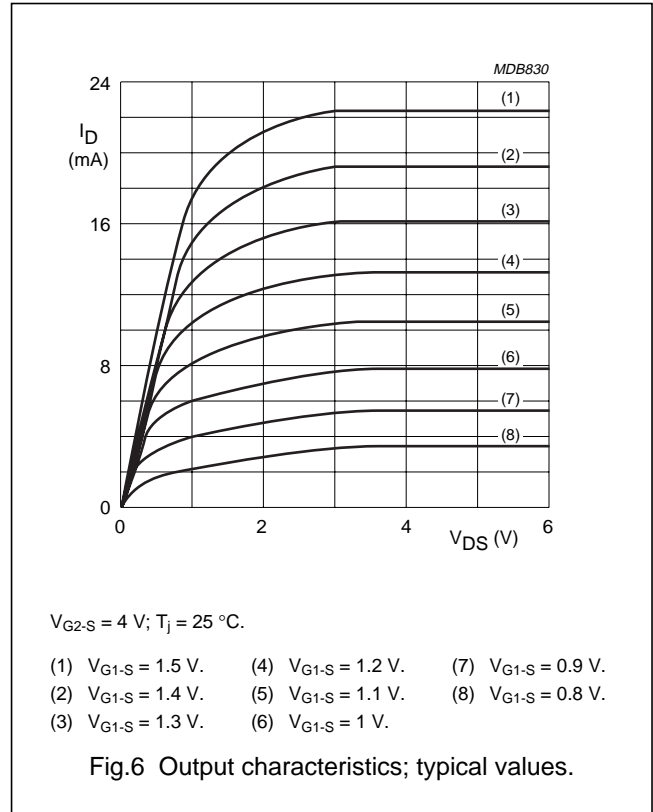
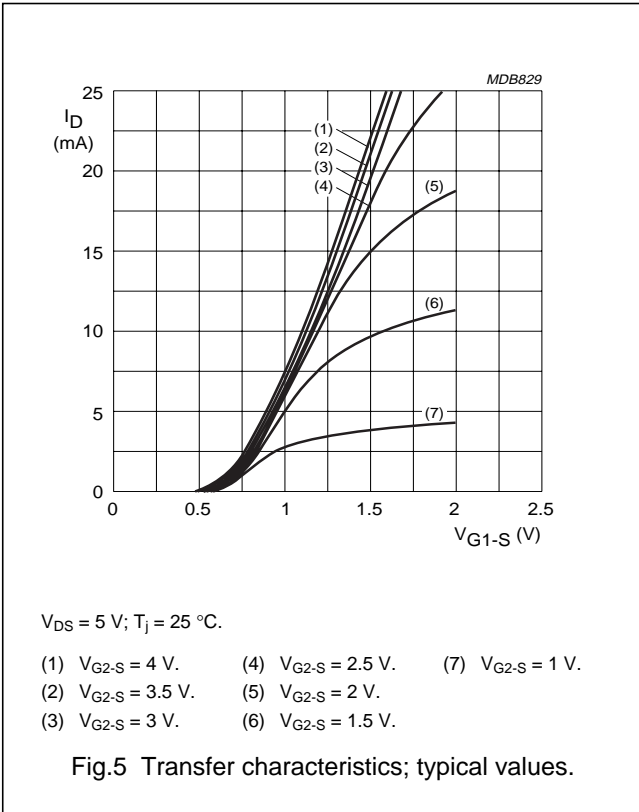
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$ y_{fs} $	forward transfer admittance	pulsed; $T_j = 25\text{ °C}$	25	30	40	mS
$C_{ig1-ss}$	input capacitance at gate 1	$f = 1\text{ MHz}$	–	2.1	2.6	pF
$C_{ig2-ss}$	input capacitance at gate 2	$f = 1\text{ MHz}$	–	1.1	–	pF
$C_{oss}$	output capacitance	$f = 1\text{ MHz}$	–	0.9	–	pF
$C_{rss}$	reverse transfer capacitance	$f = 1\text{ MHz}$	–	15	30	fF
F	noise figure	$f = 11\text{ MHz}$ ; $G_S = 20\text{ mS}$ ; $B_S = 0$	–	3.5	–	dB
		$f = 400\text{ MHz}$ ; $Y_S = Y_{S(opt)}$	–	0.9	1.6	dB
		$f = 800\text{ MHz}$ ; $Y_S = Y_{S(opt)}$	–	1.3	2	dB
$G_{tr}$	power gain	$f = 200\text{ MHz}$ ; $G_S = 2\text{ mS}$ ; $B_S = B_{S(opt)}$ ; $G_L = 0.5\text{ mS}$ ; $B_L = B_{L(opt)}$	–	34	–	dB
		$f = 400\text{ MHz}$ ; $G_S = 2\text{ mS}$ ; $B_S = B_{S(opt)}$ ; $G_L = 1\text{ mS}$ ; $B_L = B_{L(opt)}$	–	29	–	dB
		$f = 800\text{ MHz}$ ; $G_S = 3.3\text{ mS}$ ; $B_S = B_{S(opt)}$ ; $G_L = 1\text{ mS}$ ; $B_L = B_{L(opt)}$	–	24	–	dB
$X_{mod}$	cross-modulation	input level for $k = 1\%$ ; $f_w = 50\text{ MHz}$ ; $f_{unw} = 60\text{ MHz}$ ; note 1				
		at 0 dB AGC	90	–	–	dB $\mu$ V
		at 10 dB AGC	–	92	–	dB $\mu$ V
	at 40 dB AGC	100	105	–	dB $\mu$ V	

**Note**

1. Measured in test circuit Fig.21.

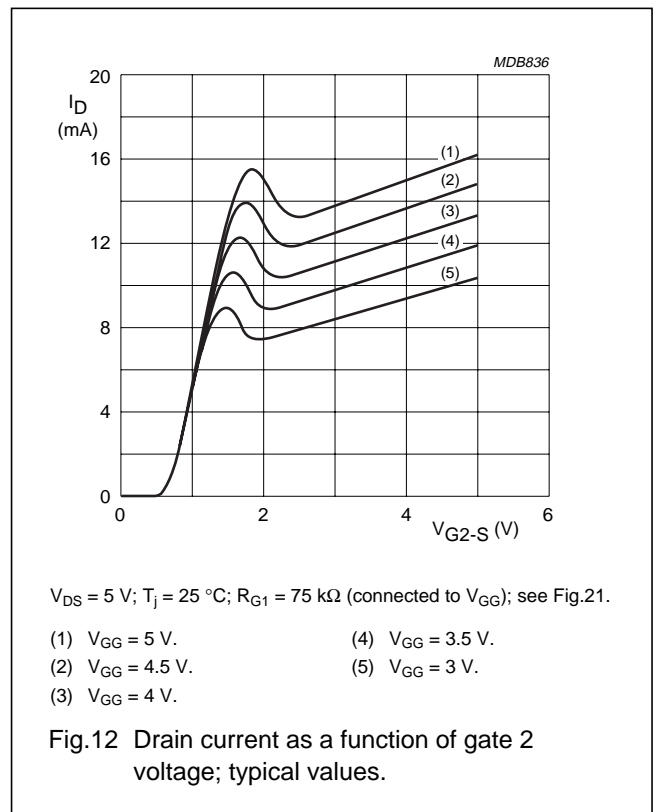
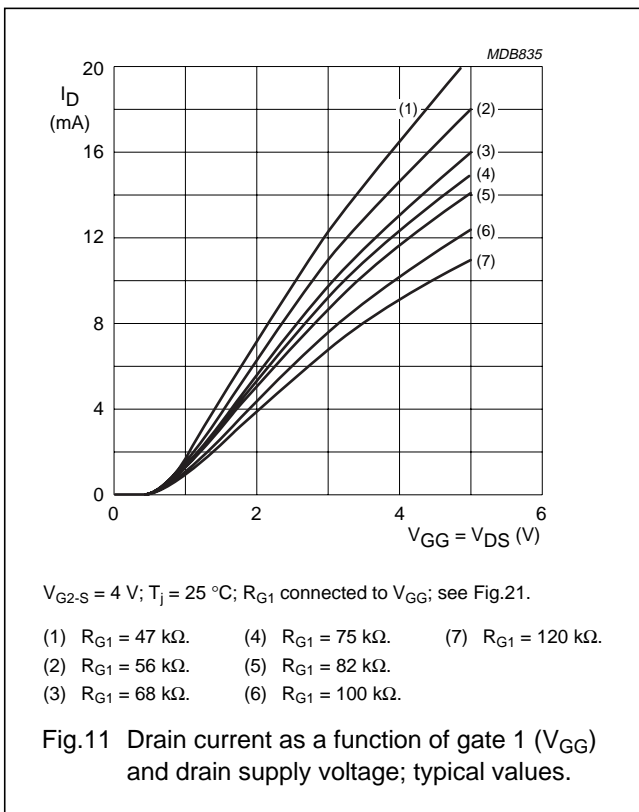
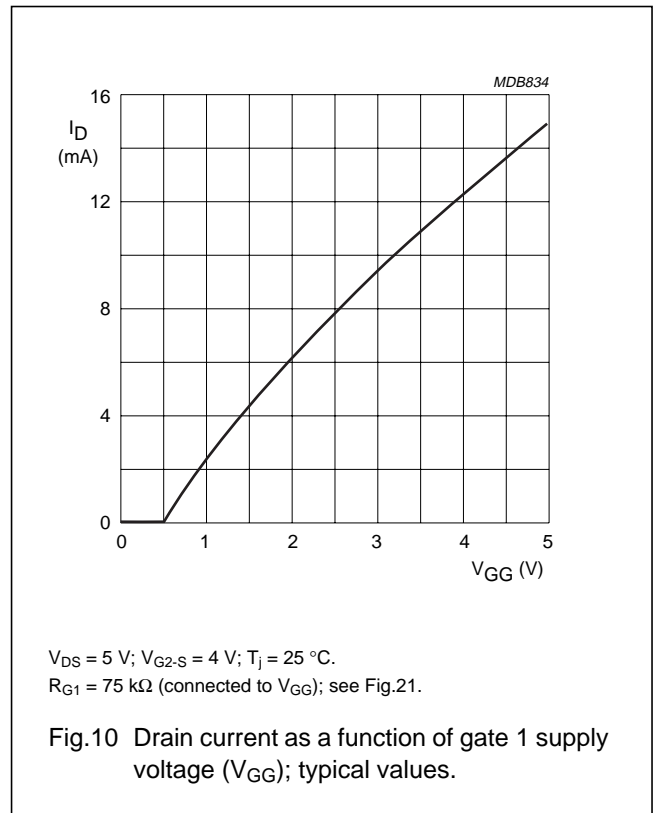
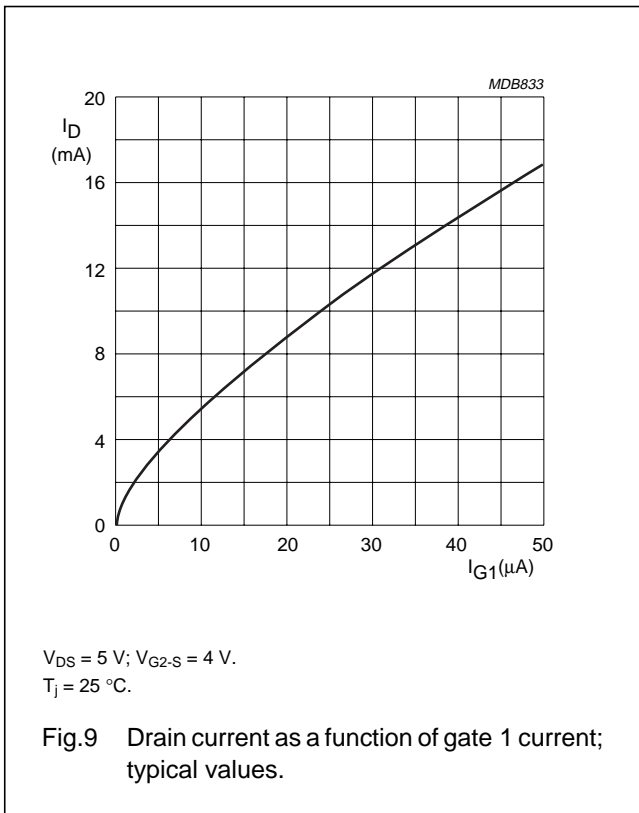
N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR



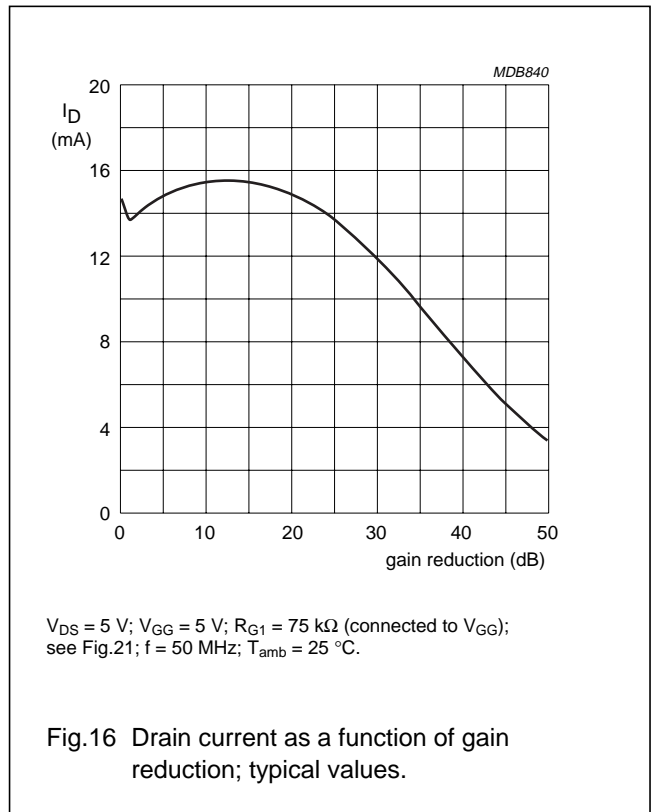
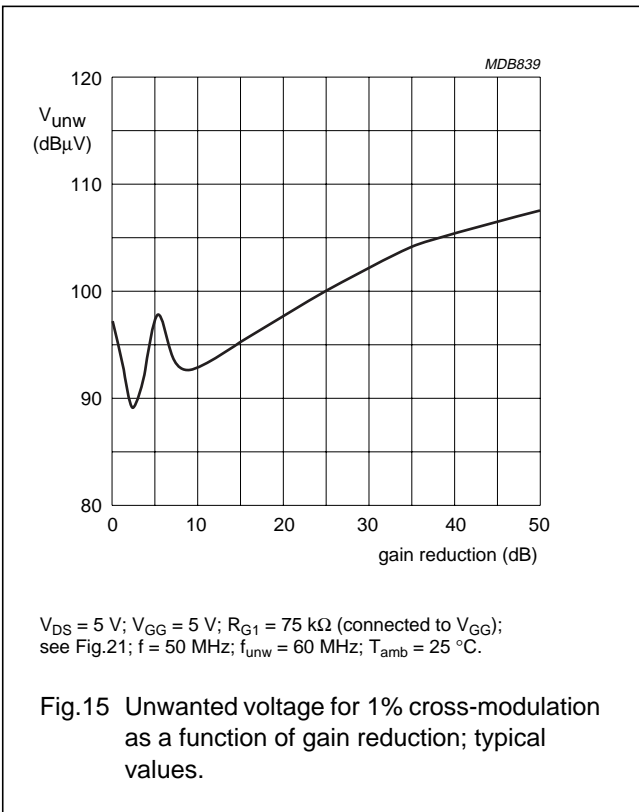
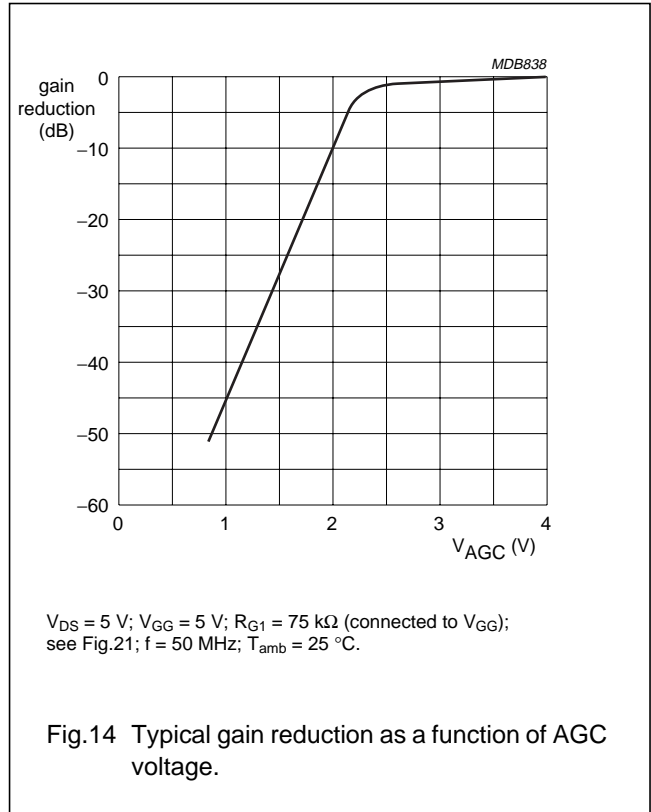
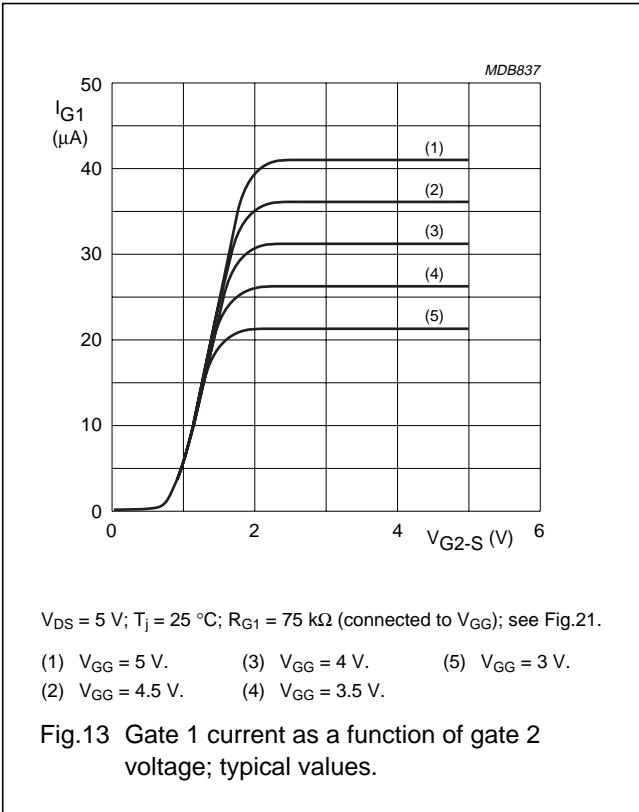
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BF1211; BF1211R; BF1211WR



N-channel dual-gate MOS-FETs

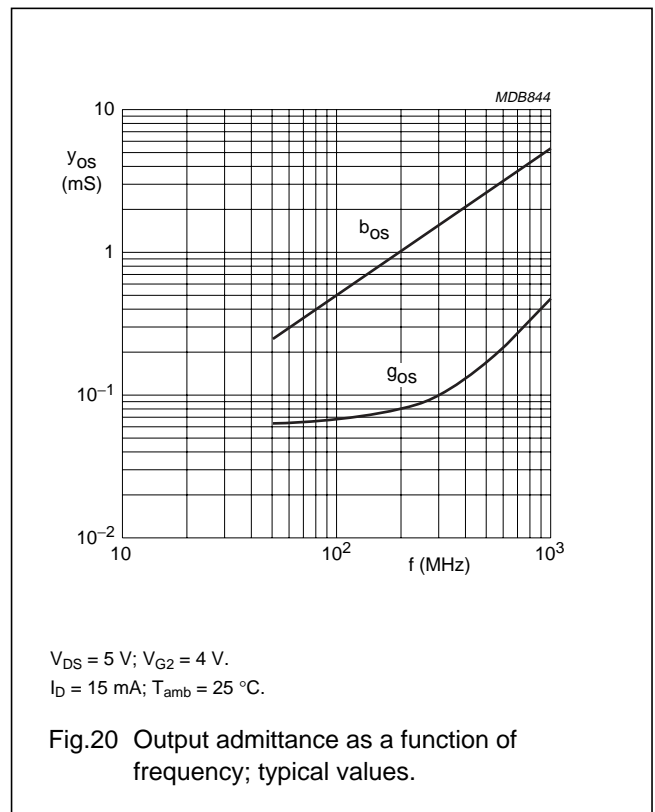
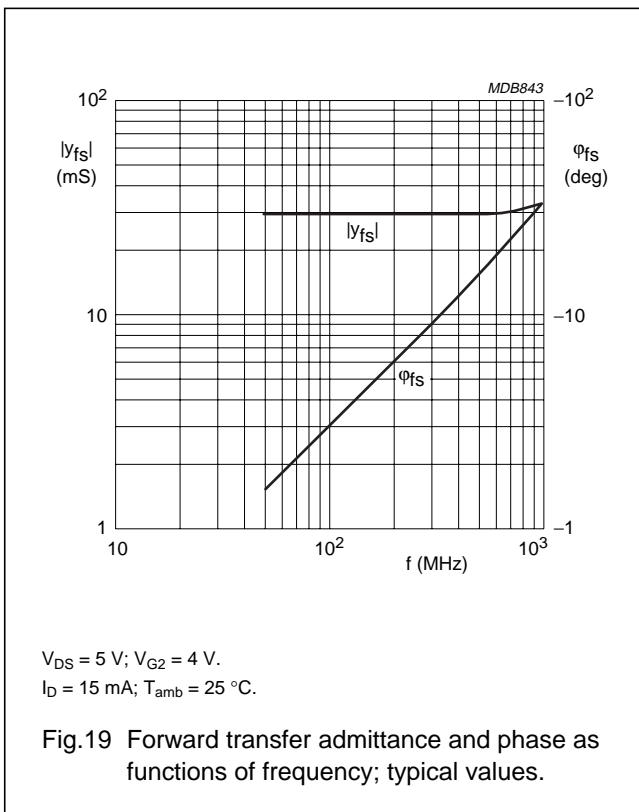
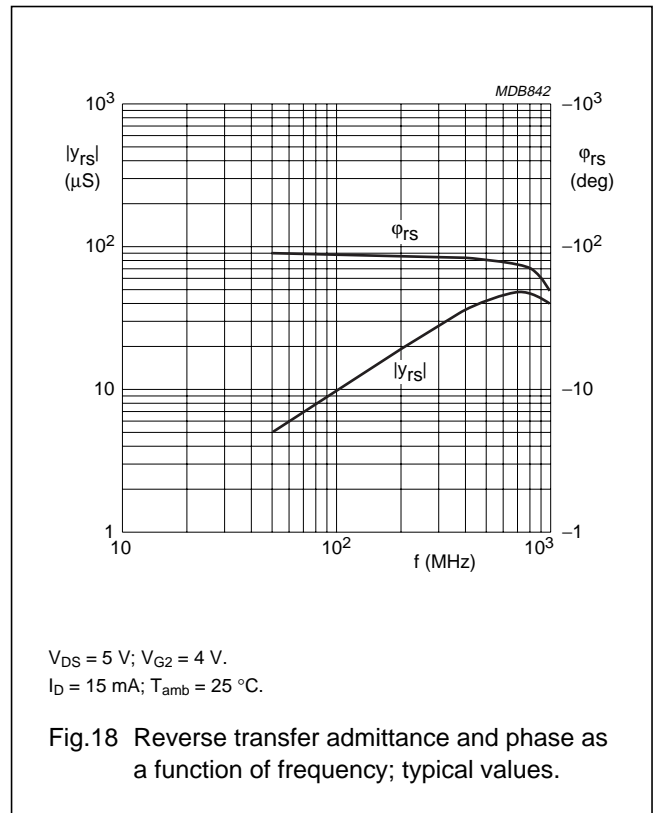
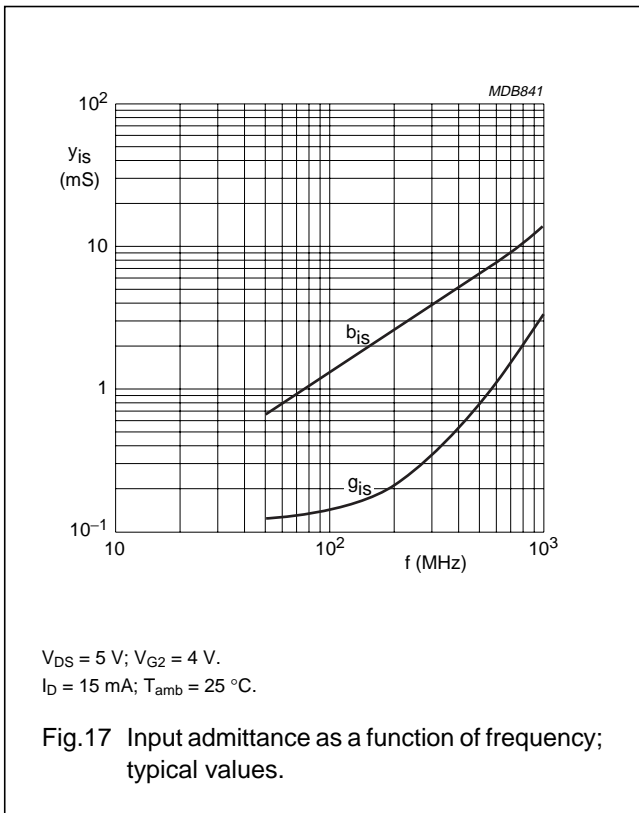
BF1211; BF1211R; BF1211WR





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BF1211; BF1211R; BF1211WR

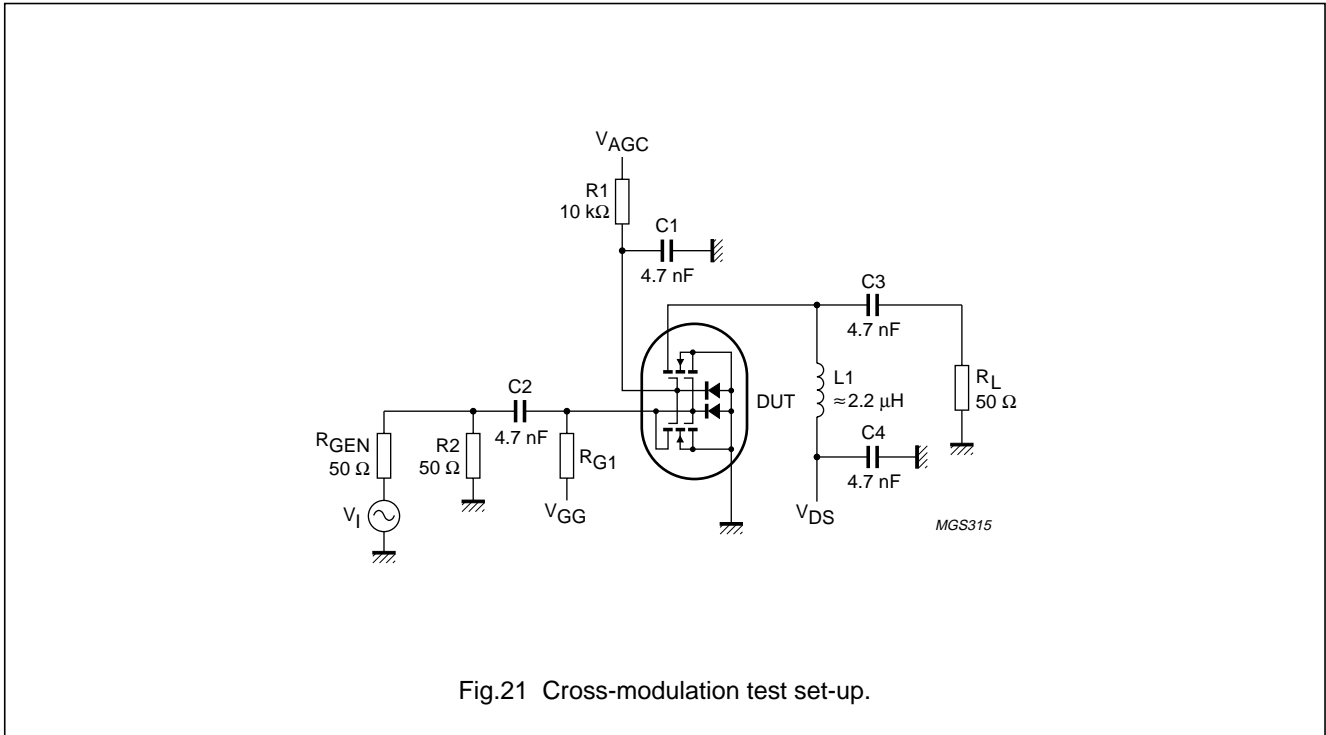


Fig.21 Cross-modulation test set-up.

**Table 1** Scattering parameters:  $V_{DS} = 5\text{ V}$ ;  $V_{G2-S} = 4\text{ V}$ ;  $I_D = 15\text{ mA}$ ;  $T_{amb} = 25\text{ }^\circ\text{C}$

f (MHz)	S <sub>11</sub>		S <sub>21</sub>		S <sub>12</sub>		S <sub>22</sub>	
	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)
50	0.987	-3.86	2.928	175.8	0.0005	89.3	0.993	-1.58
100	0.985	-7.73	2.921	171.6	0.0010	86.9	0.993	-3.14
200	0.979	-15.25	2.807	163.2	0.0015	91.1	0.993	-6.31
300	0.965	-22.84	2.846	155.0	0.0028	77.4	0.988	-9.41
400	0.949	-30.15	2.784	146.7	0.0034	74.0	0.985	-12.48
500	0.929	-30.25	2.704	138.9	0.0037	71.4	0.981	-15.54
600	0.904	-44.24	2.639	130.9	0.0040	69.6	0.976	-18.59
700	0.876	-51.16	2.558	123.0	0.0039	69.0	0.971	-21.65
800	0.846	-58.16	2.486	115.1	0.0037	70.0	0.965	-24.27
900	0.816	-65.15	2.402	107.2	0.0032	74.5	0.960	-27.79
1000	0.791	-72.22	2.315	99.9	0.0028	87.1	0.956	-30.94

**Table 2** Noise data:  $V_{DS} = 5\text{ V}$ ;  $V_{G2-S} = 4\text{ V}$ ;  $I_D = 15\text{ mA}$ ;  $T_{amb} = 25\text{ }^\circ\text{C}$

f (MHz)	F <sub>min</sub> (dB)	Γ <sub>opt</sub>		R <sub>n</sub> (Ω)
		(ratio)	(deg)	
400	0.9	0.693	16.75	29.85
800	1.3	0.707	37.33	29.90

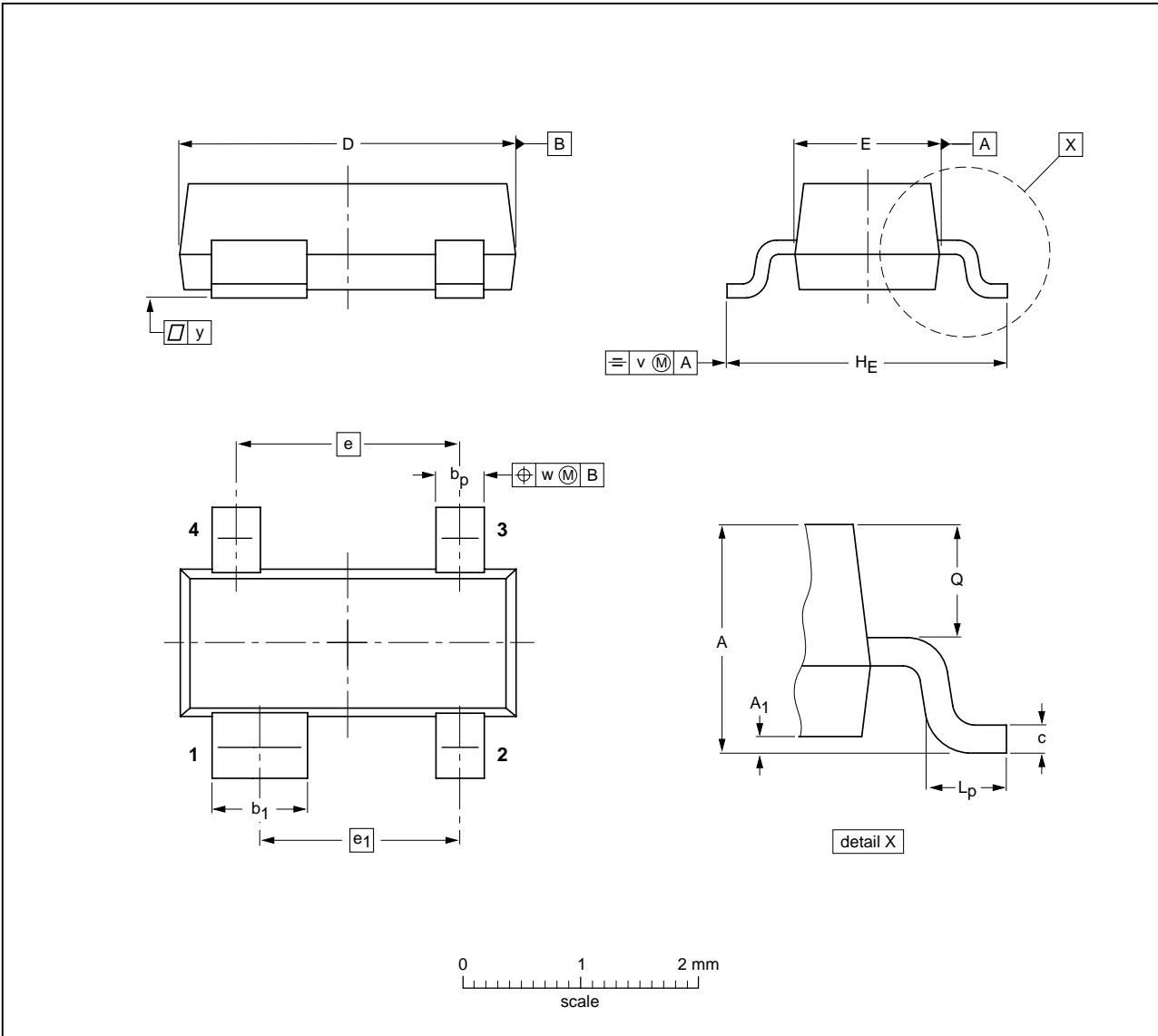
N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

PACKAGE OUTLINES

Plastic surface mounted package; 4 leads

SOT143B



DIMENSIONS (mm are the original dimensions)

UNIT	A	A <sub>1</sub> max	b <sub>p</sub>	b <sub>1</sub>	c	D	E	e	e <sub>1</sub>	H <sub>E</sub>	L <sub>p</sub>	Q	v	w	y
mm	1.1 0.9	0.1	0.48 0.38	0.88 0.78	0.15 0.09	3.0 2.8	1.4 1.2	1.9	1.7	2.5 2.1	0.45 0.15	0.55 0.45	0.2	0.1	0.1

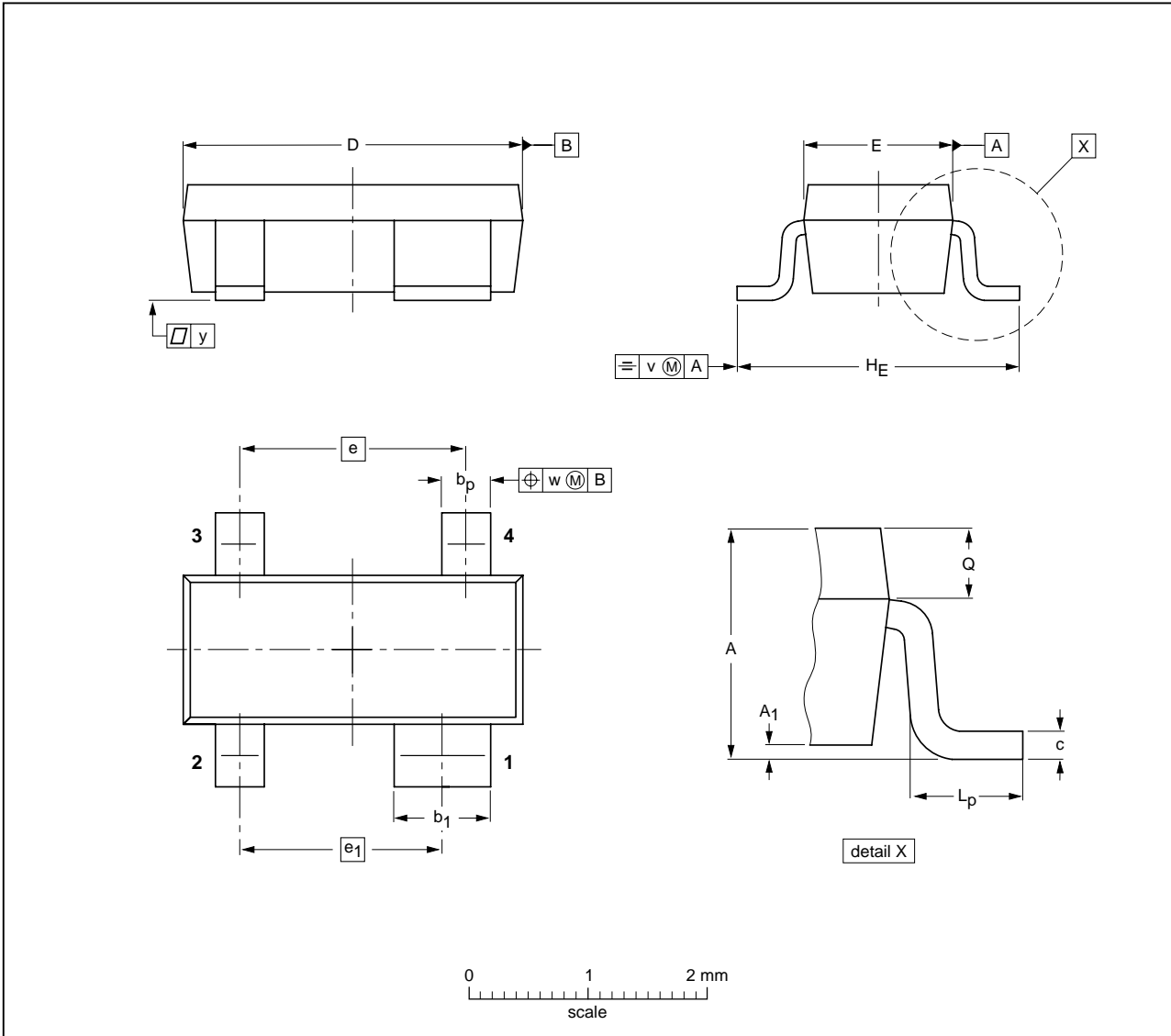
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	IEC	JEDEC	EIAJ			
SOT143B						97-02-28

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

Plastic surface mounted package; reverse pinning; 4 leads

SOT143R



DIMENSIONS (mm are the original dimensions)

UNIT	A	A <sub>1</sub> max	b <sub>p</sub>	b <sub>1</sub>	c	D	E	e	e <sub>1</sub>	H <sub>E</sub>	L <sub>p</sub>	Q	v	w	y
mm	1.1 0.9	0.1	0.48 0.38	0.88 0.78	0.15 0.09	3.0 2.8	1.4 1.2	1.9	1.7	2.5 2.1	0.55 0.25	0.45 0.25	0.2	0.1	0.1

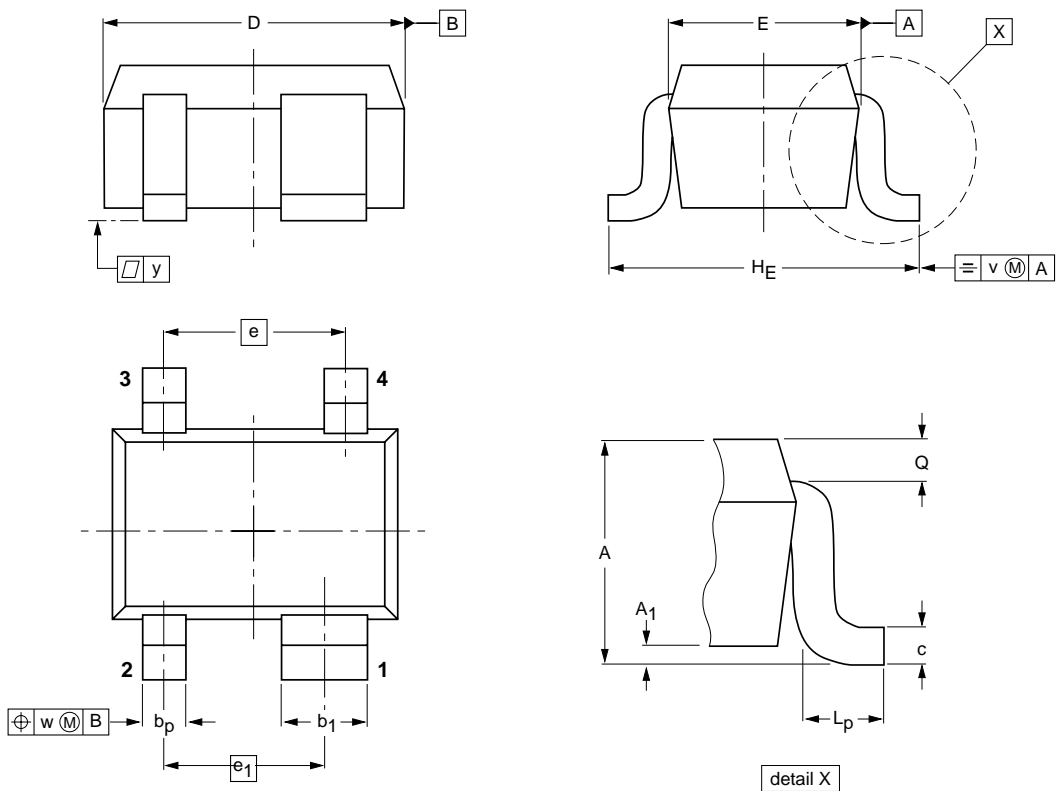
OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
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SOT143R			SC-61B			97-03-10 99-09-13

N-channel dual-gate MOS-FETs

BF1211; BF1211R; BF1211WR

Plastic surface mounted package; reverse pinning; 4 leads

SOT343R



**DIMENSIONS (mm are the original dimensions)**

UNIT	A	A <sub>1</sub> max	b <sub>p</sub>	b <sub>1</sub>	c	D	E	e	e <sub>1</sub>	H <sub>E</sub>	L <sub>p</sub>	Q	v	w	y
mm	1.1 0.8	0.1	0.4 0.3	0.7 0.5	0.25 0.10	2.2 1.8	1.35 1.15	1.3	1.15	2.2 2.0	0.45 0.15	0.23 0.13	0.2	0.2	0.1

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT343R						97-05-21

## N-channel dual-gate MOS-FETs

## BF1211; BF1211R; BF1211WR

## DATA SHEET STATUS

LEVEL	DATA SHEET STATUS <sup>(1)</sup>	PRODUCT STATUS <sup>(2)(3)</sup>	DEFINITION
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
III	Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Relevant changes will be communicated via a Customer Product/Process Change Notification (CPCN).

## Notes

1. Please consult the most recently issued data sheet before initiating or completing a design.
2. The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL <http://www.semiconductors.philips.com>.
3. For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.

## DEFINITIONS

**Short-form specification** — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

**Limiting values definition** — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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Printed in The Netherlands

R77/01/pp15

Date of release: 2003 Dec 16

Document order number: 9397 750 12003

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